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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

R. Carlotte and the control of the c	
Application Serial No	10/620,468
Confirmation No	8630
Filing Date	July 15, 2003
Inventor	
Assignee	Micron Technology, Inc.
Group Art Unit	
Examiner	T. Tran
Customer No	021567
Attorney's Docket No	Ml22-2345
Title: Conductive Connection Forming Methods, Oxid	dation Reducing Methods, and
Integrated Circuits Formed Thereby	-

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Reference -See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed after the filing of the Request for Continued Examination (RCE) Application and before receipt of the first Office Action. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 09 Dec 2005

By:

Reg. No. 44,854

Form PTO-	Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2345			SERIAL NO. 10/620,468				
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		FILING DATE July 15, 2003				GROUP 2822				
U.S. PATENT DOCUMENTS										
*Examiner's Initials		Document Number	Date	Name	Name		Subclass	Filing Date If Appropriate		
	AA	6,107,179 A	08/2000	Zomorrodi et al.						
	AB	6,417,575 B2	07/2002	Harada et al.						
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										